

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/747,888 | Applicant(s)/Patent Under Reexamination JEONG, CHI WEON | |
| | Examiner Leonard R. Leo | Art Unit 3753 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| | A | US-5,184,673 | 02-1993 | Hedman et al. | 165/153 |
| | B | US-5,538,077 | 07-1996 | So et al. | 165/153 |
| | C | US-5,794,691 | 08-1998 | Evans et al. | 165/153 |
| | D | US-4,712,612 | 12-1987 | Okamoto et al. | 165/153 |
| | E | US-5,417,280 | 05-1995 | Hayashi et al. | 165/153 |
| | F | US-5,832,989 | 11-1998 | Osakabe et al. | 165/153 |
| | G | US-6,170,567 | 01-2001 | Nakada et al. | 165/153 |
| | H | US-6,460,613 | 10-2002 | Nash et al. | 165/153 |
| | I | US-6,823,933 | 11-2004 | Chiba | 165/153 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.